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Title: DeepMutation: Mutation Testing of Deep Learning Systems

Author(s): Ma, L (Ma, Lei); Zhang, FY (Zhang, Fuyuan); Sun, JY (Sun, Jiyuan); Xue, MH (Xue, Minhui); Li, B (Li, Bo); Juefei-Xu, F (Juefei-Xu, Felix); Xie, C (Xie, Chao); Li, L (Li, Li); Liu, Y (Liu, Yang); Zhao, JJ (Zhao, Jianjun); Wang, YD (Wang, Yadong)

Edited by: Ghosh S; Natella R; Cukic B; Poston R; Laranjeiro N

Source: 2018 29TH IEEE INTERNATIONAL SYMPOSIUM ON SOFTWARE RELIABILITY ENGINEERING (ISSRE) **Book Series:** Proceedings International Symposium on Software Reliability Engineering **Pages:** 100-111 **DOI:** 10.1109/ISSRE.2018.00021 **Published:** 2018

Accession Number: WOS:000467991300010

Conference Title: 29th IEEE International Symposium on Software Reliability Engineering (ISSRE)

Conference Date: OCT 15-18, 2018

Conference Location: Memphis, TN

Conference Sponsors: IEEE, IEEE Comp Soc, FedEx, Google, Nokia Bell Labs, IEEE Reliabil Soc

Author Identifiers:

Author	Web of Science ResearcherID	ORCID Number
Li, Li	AAR-3316-2020	
Liu, Yang	D-2306-2013	0000-0001-7300-9215
Xue, Minhui		0000-0002-9172-4252

ISSN: 1071-9458

ISBN: 978-1-5386-8321-7